



FINAL PRODUCT/PROCESS CHANGE NOTIFICATION #16730Generic Copy

Issue Date: 27-Jun-2012

TITLE: Release of an additional tester platform (Micro Flex) for the C623-NQ Package (currently tested on TMT tester platform)

PROPOSED FIRST SHIP DATE: 27-Sep-2012 or earlier upon customer approval (target date: 21-Jul-2012)

AFFECTED CHANGE CATEGORY(S): Final test and QC insertions

FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:

Contact your local ON Semiconductor Sales Office or your customer quality interface or Jean-Jacques Goubet < Jean-Jacques.Goubet@onsemi.com >

SAMPLES: Contact your local ON Semiconductor Sales Office

NOTIFICATION TYPE:

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 90 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact <quality@onsemi.com>.

DESCRIPTION AND PURPOSE:

Release of Micro FLEX tester platform for Final Test and QC to improve tester capacity balancing and loading:

Qualification data:

QC ambient correlation data between the source tester (TMT) and the target tester (Micro FLEX) is provided in a separate qualification report (*see attached AMIS30623C623B(R)G_QCA_TMT-uFlex_Correlation_report.docx*) together with this Final PCN.

The correlation procedure that has been used is the same as in previous PCN's covering the release of additional tester platforms:

- 2 correlation units have been serialized and datalogged in 30 loops using the source tester platform where the device is already qualified. The test was done at room temperature, using the QC program.
- Then, the same correlation units were used to gather data on target tester microFLEX.
- The same datalogging procedure used for TMT has been followed for microFLEX.

**INITIAL PRODUCT/PROCESS CHANGE NOTIFICATION #16730**

Full parametric correlation will be performed and for every test the shift will be evaluated as follows:

$$\Delta\text{mean} = \text{abs}(\text{mean}(\text{ref}) - \text{mean}(\text{qual}))$$

$$\Delta\text{sigma} = 0$$

$$\Delta\text{sigma} = \text{sigma}(\text{qual}) - \text{sigma}(\text{ref})$$

if $\text{sigma}(\text{qual}) < \text{sigma}(\text{ref})$

if $\text{sigma}(\text{qual}) > \text{sigma}(\text{ref})$

$$\text{shift} = \Delta\text{mean} + 4 * \Delta\text{sigma}$$

If $\text{shift} < \max(5\% \text{ specwidth}, 6 * \text{sigma}(\text{ref}))$ then correlation is OK for this test,
else correlation is NOK for this test

Any parameter that is NOK is independently analyzed and explained.

ELECTRICAL CHARACTERISTIC SUMMARY:

Electrical Performance will continue to meet specifications.

List of affected Customer Specific Parts:

Internal ONSEMI sellable code	External ONSEMI part number
0C623-011-XTD	AMIS30623C623BG
0C623-011-XTP	AMIS30623C623BRG